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LIST OF THE LEVE ONS CITED BY APPLICANT			Atty. Docket No. SEL 213	<u>Serial No.</u> 09/685,698			
			<u>Applicant</u> Shunpei YAMAZAKI et al				
			<u>Filing Date</u> October 10, 2000	<u>Group</u> 2813			
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